

description

The TRF6151C is a quadruple-band transceiver IC suitable for GSM850, GSM900, DCS1800, and PCS1900 GPRS class-12 applications. This device integrates a receiver based on direct conversion architecture, a transmitter based on modulation-loop architecture, frequency synthesizing including a 26-MHz VCXO, a main N-integer synthesizer, two main VCOs, a programmable main-loop filter, two TX VCOs, a TX loop filter, voltage regulators to supply on-chip and off-chip RF functions, and a power-amplifier controller.

A *quad-band* application requires few external components, aside from a power amplifier and a front-end module.

The TRF6151C is housed in a 48-pin, 7×7-mm, 0,5-mm pitch QFN package.

The TRF6151C transceiver is part of a TI GSM chipset. It is compatible with TWL3014 and TWL3016 ABB chips and with TBB2100, PD751997AGZA, and OMAP730 chips.

This device combines the following functions:

- Transmit section:
 - An offset PLL with post-IQ modulator and post-offset mixer filters fully integrated on the chip
 - Two TX VCOs fully integrated on the chip
 - A TX loop filter fully integrated on the chip
 - A divider by 4 for local oscillator (LO) generation in GSM900 and GSM850
 - A divider by 2 for LO generation in DCS1800 and PCS1900
 - A programmable M divider for IF generation
 - A power-amplifier controller including all the functions required to design a power-sensing control loop, except for the sensing diodes
- Receive section:
 - A GSM900/GSM850 LNA (LNAGSM) with switchable gain
 - A DCS1800 LNA (LNADCS) with switchable gain
 - A PCS1900 LNA (LNAPCS) with switchable gain
 - Three quadrature demodulators for GSM900/GSM850 (MIXGSM), DCS1800 (MIXDCS), and PCS1900 (MIXPCS) bands with programmable gain
 - Two baseband amplifiers with digitally-programmable gain
 - Two fully-integrated baseband channel filters
 - Two dc-offset compensation systems
 - A divider by 4 for LO generation in GSM900 and GSM850 in order to minimize dc offset generated by self mixing and the LO reradiation
 - A divider by 2 for LO generation in DCS1800 and PCS1900 in order to minimize dc offset generated by self-mixing and LO reradiation.



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.



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description (continued)

- Common to both sections:
 - A 26-MHz VCXO with external varactor and crystal
 - A 26-MHz buffer to drive the DBBs
 - Two main VCOs fully integrated on the chip
 - A main N-integer synthesizer
 - A programmable main loop filter fully integrated on the chip
 - Three voltage regulators to supply internal functions and external RF components
 - A digital serial interface

Figure 1 shows the TRF6151C receiver block diagram. Figure 2 shows a top view of the RGZ package.

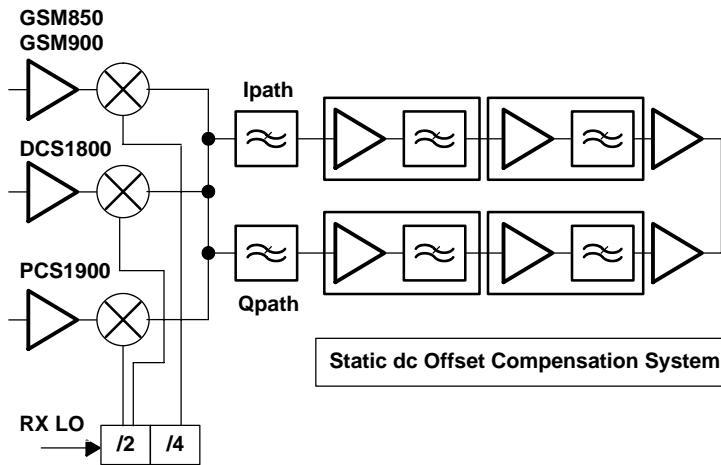


Figure 1. Receiver Block Diagram

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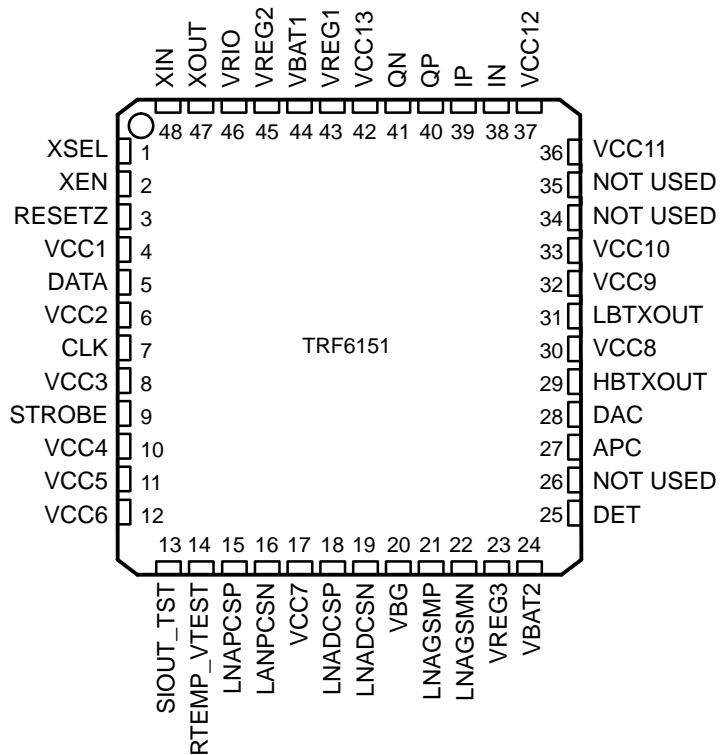


Figure 2. RGZ Package (Top View)

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Terminal Functions

TERMINAL NAME	NO.	I/O	DESCRIPTION
XSEL	1	I	Crystal selection (external or internal)
XEN	2	I	Crystal enable (VCXO and buffer supply)
RESETZ	3	I	Serial-interface reset
VCC1	4	VCC	PLL supply voltage
DATA	5	I	Serial-interface data
VCC2	6	VCC	PLL supply voltage
CLK	7	I	Serial interface clock
VCC3	8	VCC	PLL supply voltage
STROBE	9	I	Serial interface strobe
VCC4	10	VCC	MAIN V _{CO2} supply voltage (2.0 V internally generated)
VCC5	11	VCC	VCO divider supply voltage
VCC6	12	VCC	MAIN V _{CO1} supply voltage (2.0 V internally generated)
SIOUT_TST	13	O	Serial interface output multiplexed with PLL test
RTEMP_VTEST	14	O	Temperature sensor output and VCO test
LNAPCSP	15	I	RX PCS LNA input (+)
LNAPCSN	16	I	RX PCS LNA input (-)
VCC7	17	VCC	RX LNA supply voltage
LNADCSP	18	I	RX DCS LNA input
LNADCSN	19	I	RX DCS LNA input
VBG	20	O	Band gap voltage output
LNAGSMP	21	I	RX GSM LNA input (+)
LNAGSMN	22	I	RX GSM LNA input (-)
VREG3	23	O	Regulator 3 output dedicated to VCC8 and VCC10
VBAT2	24	I	Regulator 3 battery-voltage supply
DET	25	I	PA controller detect input (ground if not used)
Not used	26	-	Not used—grounded
APC	27	O	PA controller output (float if not used)
DAC	28	I	PA controller APC input (ground if not used)
HBTXOUT	29	O	TX DCS/PCS output
VCC8	30	VCC	TX VCO buffer supply voltage (2.7 V)
LBTXOUT	31	O	TX GSM900/GSM850 output
VCC9	32	VCC	TX HB VCO core-supply voltage (2.4 V internally generated)
VCC10	33	VCC	TX VCO and RX mixer supply voltage
Not used	34	-	Not used
Not used	35	-	Not used
VCC11	36	VCC	TX LB VCO core-supply voltage (2.4 V internally generated)
VCC12	37	VCC	IQ modulator supply voltage and RX VGA supply voltage (2.7 V)
IN	38	I/O	In-phase baseband I/O (-)
IP	39	I/O	In-phase baseband I/O (+)
QP	40	I/O	Quadrature-phase baseband I/O (+)
QN	41	I/O	Quadrature-phase baseband I/O (-)
VCC13	42	VCC	TX charge pump supply voltage (2.7 V)
VREG1	43	O	Regulator 1 output dedicated to VCC7, VCC12, and VCC13



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Terminal Functions (continued)

TERMINAL NAME	NO.	I/O	DESCRIPTION
VBAT1	44	I	Regulator 1 and regulator 2 battery-voltage supply
VREG2	45	O	Regulator 2 output dedicated to VCC1, VCC2, VCC3, and VCC5
VRIO	46	VCC	Serial interface supply voltage
XOUT	47	O	Crystal buffer output
XIN	48	I	Crystal input

absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range: V_{BAT} -0.3 V to 5.5 V
 Power dissipation, $T_a = 25\text{ }^\circ\text{C}$, 48-Pin QFN 7x7 mm, 0.5 mm pitch 3.06 W
 Operating temperature range T_C -25°C to +85°C
 Storage temperature range T_{stg} -65°C to +150°C
 ESD integrity (HBM)‡ 1.5 kV
 ESD integrity (CDM) 300 V

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

‡ RF pins (LNAGSMP/N, LNADCSP/N, LNAPCSP/N, LBTXOUT & HBTXOUT) are rated at 1 KV HBM.

recommended operating conditions

	MIN	TYP	MAX	UNIT
V_{RIO} Supply voltage	2.7	2.8	2.9	V
V_{IH} High-level input voltage	$0.8 \cdot V_{RIO}$			V
V_{IL} Low-level input voltage	$0.22 \cdot V_{RIO}$			V
V_{OH} High-level output voltage	$0.7 \cdot V_{RIO}$		$V_{RIO} + 0.5$	V
V_{OL} Low-level output voltage	-0.5		$0.3 \cdot V_{RIO}$	V
V_{CC} Supply voltage	2.7	2.8	2.9	V
V_{BAT} Supply voltage	3.0^\dagger	3.6	5.5	V

† 3.0 V corresponds to V_{BATMIN} ==> When MS is emitting at full power, the battery voltage must never be under 3.0 V at TRF6151C regulator inputs

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total current consumption

off mode

POWER MODE	TEST CONDITIONS	BAND	MIN	TYP	MAX	UNIT
All off	All functional blocks powered off	-		20	40	μA
All off except band gap	Band gap on and all other functional blocks powered off	-		80	100	μA
All off except band gap and regulators	Band gap and regulators on and all other functional blocks powered off	-		0.6	0.7	mA

receive mode

POWER MODE	TEST CONDITIONS	BAND	MIN	TYP	MAX	UNIT
RX synthesizer on	Main PLL is locking	GSM850		8	8.2	mA
		GSM900		8	8.2	
		DCS1800		8	8.2	
		PCS1900		8	8.2	
RX on in high gain	Main PLL, LO generation, LNA, IQ demodulator, and baseband strip are on	GSM850		62	80.4	mA
		GSM900		62	80.5	
		DCS1800		66	85.3	
		PCS1900		66	85.3	

transmit mode

POWER MODE	TEST CONDITIONS	BAND	MIN	TYP	MAX	UNIT
TX synthesizer on	Main PLL is locking	GSM850L		6.3	8.2	mA
		GSM850H		6.3	8.2	
		GSM900		6.3	8.2	
		DCS1800		6.3	8.2	
		PCS1900		6.3	8.2	
TX on	Main PLL, offset PLL, LO/IF generation, IQ modulator, and PA controller are on	GSM850L		116.0	132.5	mA
		GSM850H		116.0	132.5	
		GSM900		116.0	132.4	
		DCS1800		106.0	117.8	
		PCS1900		106.0	117.8	

† VCXO (supplied by an external voltage source) typical current consumption is 2.7 mA



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voltage regulation

Typical: $V_{CC} = 2.8\text{ V}$, $T_a = +25^\circ\text{C}$

$C_{out} = 1.0\ \mu\text{F}$, $C_{bandgap} = 100\ \text{nF}$, unless otherwise specified

Table specifies regulator and bandgap together unless otherwise specified.

If an external regulation is desired, the internal voltage regulators can be bypassed (regulators shut down).

Typical: $V_{CC} = 2.8\text{ V}$, $T_a = +25^\circ\text{C}$ - Min and max: $T_a = -25^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{BAT} = 3.0\text{ V}$ to 5.5 V and over process.

bandgap

PARAMETERS	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNIT
Turnon time	Speed up mode active				25	ms
Current consumption				80		μA

regulators R1, R2, and R3

PARAMETERS	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNIT
Input voltage		V_I	3.0 [†]	3.6	5.5	V
Output voltage	@ I_{Omax}	V_O	2.7	2.8	2.9	V
Max output current		I_{Omax}	60			mA
Ground pin current	@ I_{Omax}			2.1	6.0	mA
dc line regulation	R1	From V_{Imin} to V_{Imax} @ I_{Omax}		-10.5	50	mV
	R2			-10	50	
	R3			-13.5	50	
ac line regulation	Overshoot [‡]	V_I step from $V_O + 0.1$ to $V_O + 0.5$ in $30\ \mu\text{s}$			20	mV
	Undershoot [‡]	V_I step from $V_O + 0.5$ to $V_O + 0.1$ in $30\ \mu\text{s}$			20	
dc load regulation	R1	$I_O = 0\ \text{mA}$ to I_{Omax}		-9	50	mV
	R2			-8	50	
	R3			-13	50	
ac load regulation	Overshoot [‡]	I_O step from I_{Omax} to $I_{Omax}/2$ in $5\ \mu\text{s}$			30	mV
	Undershoot [‡]	I_O step from $I_{Omax}/2$ to I_{Omax} in $5\ \mu\text{s}$			30	
Output voltage noise	$f = 10\ \text{Hz}$ to $100\ \text{kHz}$ $I_O = I_{Omax}$ $V_I = V_O + 0.2\ \text{V}$			28	50	μVrms
ESR of decoupling capacitor [§]			0.01		1	Ω
Turnon time	V_O step from 0 to $V_{Omax} \pm 3\%$ @ I_{Omax}				100 [¶]	μs
Ripple rejection	ac amplitude = $50\ \text{mVp}$ $f = 100\ \text{Hz}$ @ I_{Omax} $V_I = 3.1\ \text{V}$			64	55	dB
	ac amplitude = $50\ \text{mVp}$ $f = 500\ \text{kHz}$ @ I_{Omax} $V_I = 3.1\ \text{V}$			40	35	dB

[†] 3.0 V corresponds to V_{BATMIN} ==> When MS is emitting at full power, the battery voltage must never be under 3.0 V at TRF6151C regulators inputs

[‡] Ensured by design

[§] Measurements taken with decoupling capacitor having ESR within specified range

[¶] Band gap turn-on time not included



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voltage regulation (continued)

regulator power domains

FUNCTIONAL BLOCKS	SUPPLY VOLTAGE	REGULATED SUPPLY	VCC LINE
Receiver			
LNAGSM, LNADCS, LNAPCS	V _{BAT1}	V _{REG1}	V _{CC7}
Analog part of VGA	V _{BAT1}	V _{REG1}	V _{CC12}
IQ demodulators (MIXGSM, MIXDCS, and MIXPCS)	V _{BAT2}	V _{REG3}	V _{CC8}
Transmitter			
Charge pump	V _{BAT1}	V _{REG1}	V _{CC13}
Phase frequency detector	V _{BAT1}	V _{REG1}	-†‡
Offset mixer, post-offset mixer low-pass filter	V _{BAT1}	V _{REG1}	V _{CC7}
Offset mixer buffer	V _{BAT2}	V _{REG3}	V _{CC10}
IQ modulator, post-IQ modulator low-pass filter	V _{BAT1}	V _{REG1}	V _{CC12}
TX LB VCO	V _{CC10}	2.4-V internal regulator	V _{CC11} ‡
TX HB VCO	V _{CC10}	2.4-V internal regulator	V _{CC9} ‡
TX VCO output buffers	V _{BAT2}	V _{REG3}	V _{CC8}
PA controller	V _{BAT1}	V _{REG1}	V _{CC7}
Main synthesizer			
Prescaler, charge pump, phase/frequency detector	V _{BAT1}	V _{REG2}	V _{CC2}
Loop filter (operational amplifier)	V _{BAT1}	V _{REG2}	V _{CC3}
Counters A, B	V _{BAT1}	V _{REG2}	V _{CC1}
LO generation for the RX/TX (L divider, M divider)	V _{BAT1}	V _{REG2}	V _{CC5}
Main VCO2	V _{CC5}	2.0-V internal regulator	V _{CC4} §
Main VCO1	V _{CC5}	2.0-V internal regulator	V _{CC6} §
VCO calibration machine	V _{BAT2}	V _{REG3}	V _{CC10}
Reference voltage source			
Band gap	V _{BAT2}	-	-
Digital control			
PA controller timer, digital clock generator, serial interface and associated buffer, VGA digital circuitry	V _{RIO} supply from ABB chip	-	V _{RIO}
Internal 26-MHz VCXO			
VCXO core, main PLL reference divider	TCXOEN buffer (2.7 V) from DBB chip	-	XEN
Internal VCXO selection	TCXOEN buffer (2.7 V) from DBB chip	-	XSEL
RF front end module (external component)			
Front end module	V _{BAT2}	V _{REG3}	-

† Connection is done on chip (no decoupling using a V_{CC} line)

‡ Decoupling line for 2.4-V internal regulator output

§ Decoupling line for 2.0-V internal regulator output



temperature sensor†

Typical: $V_{CC} = 2.8\text{ V}$, $T_a = +25^\circ\text{C}$ - Min and max: $T_a = -25^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{BAT} = 3.0\text{ V}$ to 5.5 V and over process

PARAMETERS	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNIT
Sensor voltage	@ $T_{a\text{min.}} = -25^\circ\text{C}$		0.9		1.05	V
	@ $T_{a\text{max.}} = +85^\circ\text{C}$		1.35		1.5	
Sensor slope	Over $-25 \sim +85^\circ\text{C}$		3.0		5.0	mV/°C

† This temperature sensor is accessible any time via pin 14 (not multiplexed with any other signal)

VCXO buffer output (XOUT pin)†

PARAMETERS	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNIT
Output frequency				26		MHz
Output level			0.5	1.0	2.0	V _{PP}
Duty cycle					40/60 to 60/40	
Start up time (including the VCXO core)	90% of output amplitude			‡	9.2	ms

† Load impedance $Z_L = 25\text{ pF}$ in parallel with $10\text{ k}\Omega$ @ 26 MHz

‡ Ensured by design

The internal VCXO setup shown in Figure 3 is used in production testing.

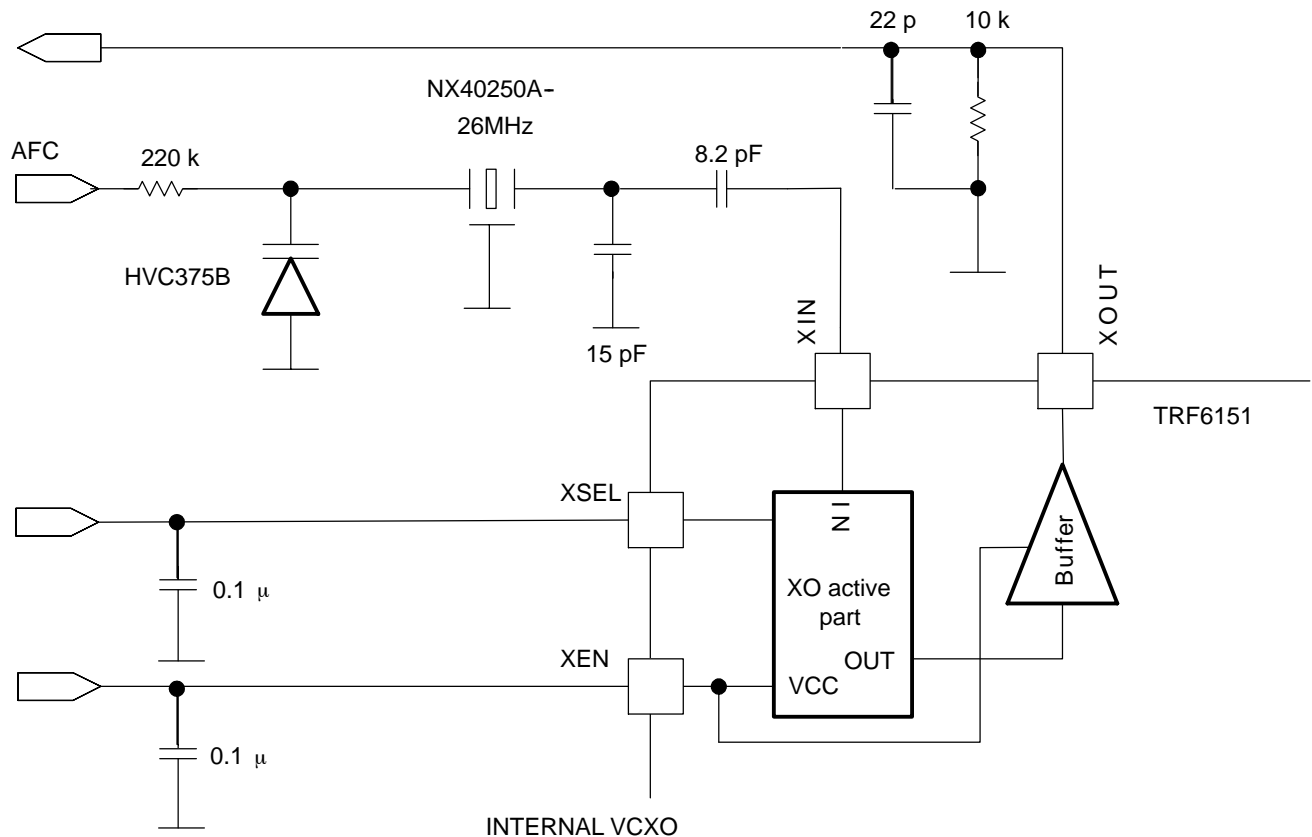


Figure 3. Internal VCXO

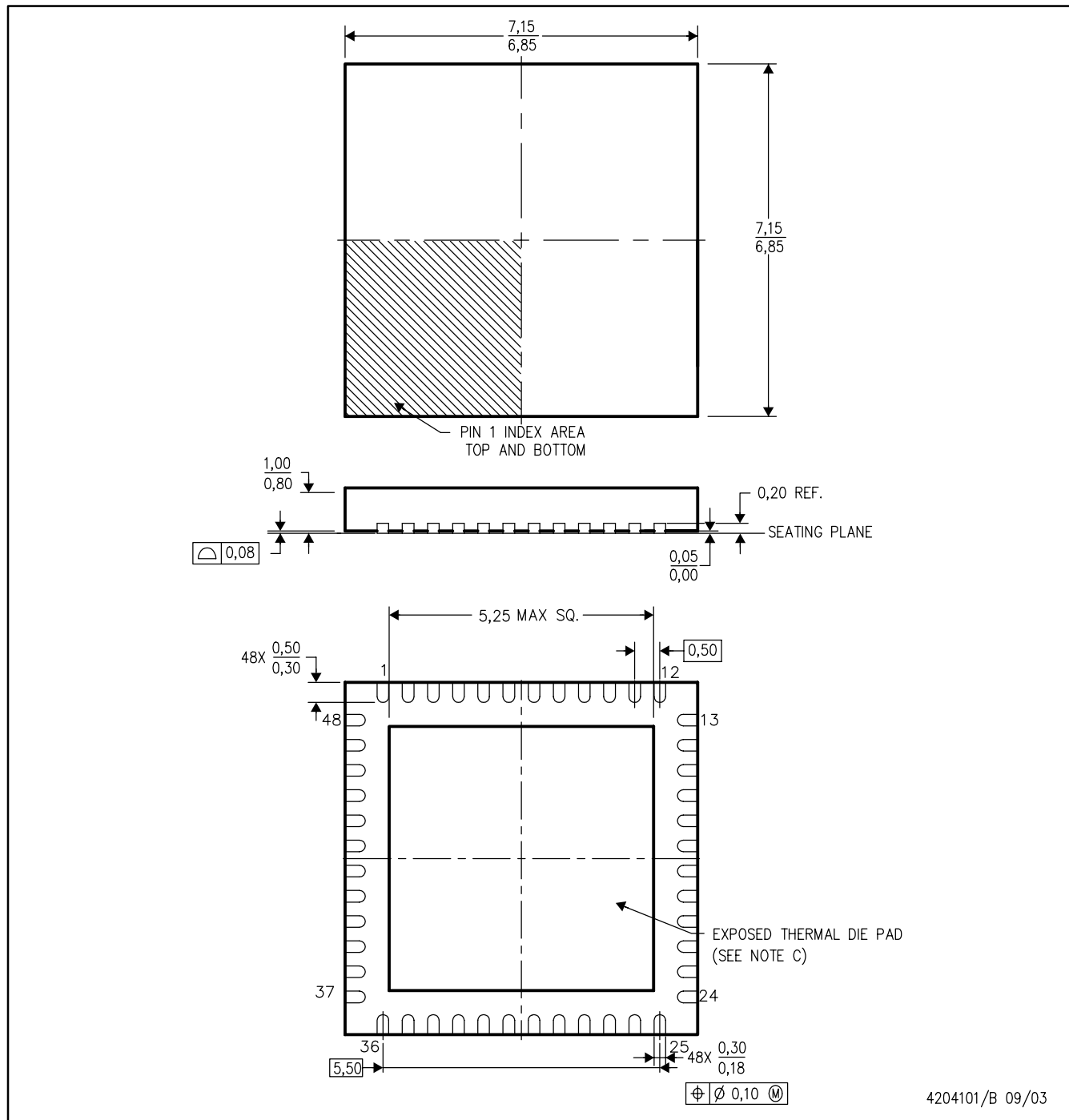
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MECHANICAL DATA

RGZ (S-PQFP-N48)

PLASTIC QUAD FLATPACK



- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Quad Flatpack, no-leads (QFN) package configuration
 - D. The package thermal performance may be enhanced by bonding the thermal pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected leads.
 - E. Falls within JEDEC MO-220

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